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	ATMI-546-CIP-I	10/784,606
	APPLICANT	
	Frank DiMeo, Jr.	
	FILING DATE	GROUP
	February 23, 2004	2856

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JD</i>	AA	10/273,036	10/17/2002	Frank DiMeo, Jr., et al.			
<i>JD</i>	AB	6,265,222	6/24/2001	Frank DiMeo, Jr., et al.			
<i>JD</i>	AC	5,679,576 A	10/21/1997	Kawai, et al.			
<i>JD</i>	AD	5,612,489 A	3/18/1997	Ragsdale, et al.			
<i>JD</i>	AE	6,428,713 B1	8/6/2002	Christenson, et al.			
<i>JD</i>	AF	4,723,438 A	2/9/1988	Adler-Golden, et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSLATION YES	NO
							X (abstract only)	

## OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)

<i>JD</i>	AG	Anderson, B, et al., Semiconductor International, October (1993)
<i>JD</i>	AH	Inorganic Solid Fluorides, Chemistry and Physics, Academic Press, 1985, Ed P. Hagenmuller. (See Information Disclosure Statement Box 1)
<i>JD</i>	AI	W. Moritz, et al., Sensors and Actuators B 24-25 (1995) 194-196, "Monitoring of HF and F2 using a field-effect sensor"
<i>JD</i>	AJ	Dr. Shigeru Kurosawa, et al., Fluorine in Coatings II, Paper 33, pgs. 1-8, "Plasma Polymerisation of Fluorine Contained Polycyclic Compounds: Its Application in Chemical Sensors"
<i>JD</i>	AK	Werner Moritz, et al., The 11th European Conference on Solid State Transucers, Warsaw, Poland, pgs. 111-114, September 21-24, 1997, "Gas Sensors for Fluorine Using Different Semiconductor Substrates"
<i>JD</i>	AL	W. Moritz, et al., 1998 American Chemical Society, Chapter 10, pgs. 119-129, "Silicon-Based Sensor for Fluorine Gas"
<i>JD</i>	AM	Semiconductor International, "Residual Gas Analysis", Oct. 1997, pgs. 94-100

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EXAMINER <i>Jacques Smith</i>	DATE CONSIDERED <i>05/17/05</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	